

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HAN ET AL.	
		Examiner Shawntina T. Fuqua	Art Unit 3742	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,104,004	08-2000	Ragland et al.	219/405
*	B	US-5,189,945	03-1993	Hennick, Donald C.	99/339
*	C	US-3,154,004	10-1964	HUCK ALFRED J	99/390
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	20020016089	03-2002	Korea		
*	O	2286111	08-1995	Great Britain		
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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